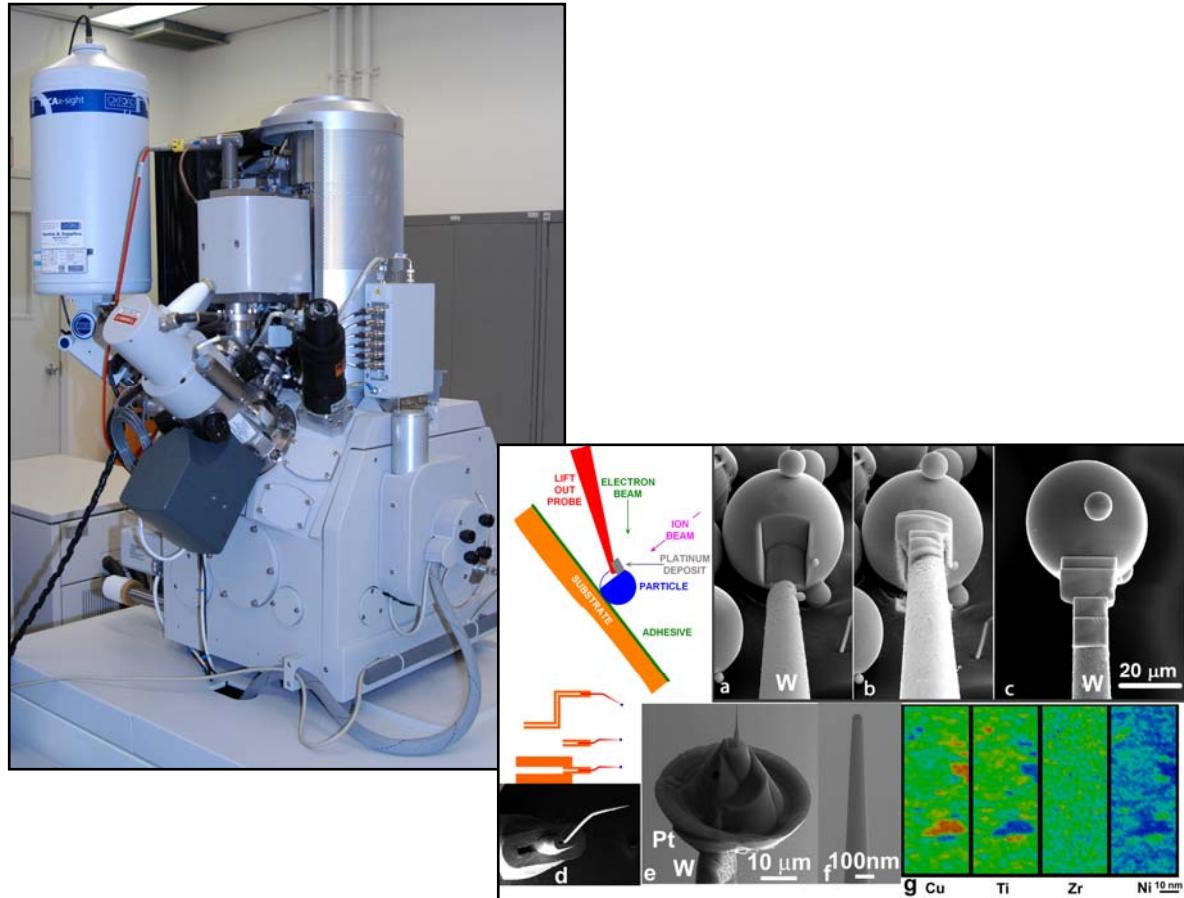


# FEI Nova 200 Dual-Beam SEM/FIB

## Capabilities:

- FEG scanning electron microscope
- Ion column with Ga liquid ion source for milling
- GIS for Pt deposition
- Kliendiek nanomanipulator for specimen lift-out
- AutoTEM, AutoFIB, and slice and view automation software



## Current Research Activities:

- Support instrument for atom probe and TEM specimen preparation
- Support instrument for nanoindentor and micropillar preparation
- 3D reconstruction of microstructural features

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